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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
09/976,708	10/12/2001	Michael C. Dorsey	P6956	2164	
7590 03/08/2004			EXAMINER		
MEYERTONS HOOD KIVLIN KOWERT & GOETZEL PC			TRIMMING	TRIMMINGS, JOHN P	
ATTN: B Noel	Kivlin				
P O Box 398			ART UNIT	PAPER NUMBER	
Austin, TX 7	8767-0398		2133	Ø	

Please find below and/or attached an Office communication concerning this application or proceeding.

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	Application No.	Applicant(s)			
	09/976,708	DORSEY, MICHAEL C.			
Office Action Summary	Examiner	Art Unit			
	John P Trimmings	2133			
The MAILING DATE of this communication app Period for Reply	pears on the cover sheet with the o	orrespondence address			
A SHORTENED STATUTORY PERIOD FOR REPLY THE MAILING DATE OF THIS COMMUNICATION.  - Extensions of time may be available under the provisions of 37 CFR 1.1 after SIX (6) MONTHS from the mailing date of this communication.  - If the period for reply specified above, is less than thirty (30) days, a reply - If NO period for reply is specified above, the maximum statutory period of Failure to reply within the set or extended period for reply will, by statute Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	36(a). In no event, however, may a reply be tir y within the statutory minimum of thirty (30) day vill apply and will expire SIX (6) MONTHS from , cause the application to become ABANDONE	nely filed  s will be considered timely. the mailing date of this communication. (C) (35 U.S.C. § 133).			
Status					
1)⊠ Responsive to communication(s) filed on 12 O	ctober 2001.				
•	action is non-final.				
· <u> </u>					
closed in accordance with the practice under E	closed in accordance with the practice under Ex parte Quayle, 1935 C.D. 11, 453 O.G. 213.				
Disposition of Claims					
<ul> <li>4)  Claim(s) 1-33 is/are pending in the application.</li> <li>4a) Of the above claim(s) is/are withdray</li> <li>5)  Claim(s) is/are allowed.</li> <li>6)  Claim(s) 1-33 is/are rejected.</li> <li>7)  Claim(s) 24, 25and 31 is/are objected to.</li> <li>8)  Claim(s) are subject to restriction and/o</li> </ul>	wn from consideration.				
Application Papers					
9)⊠ The specification is objected to by the Examine 10)⊠ The drawing(s) filed on 12 October 2001 is/are Applicant may not request that any objection to the Replacement drawing sheet(s) including the correct 11)□ The oath or declaration is objected to by the Example 11.	: a) ☐ accepted or b) ☒ objected drawing(s) be held in abeyance. Se tion is required if the drawing(s) is ob	e 37 CFR 1.85(a). ejected to. See 37 CFR 1.121(d).			
Priority under 35 U.S.C. § 119					
12) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of:  1. Certified copies of the priority document 2. Certified copies of the priority document 3. Copies of the certified copies of the priority application from the International Bureau * See the attached detailed Office action for a list	s have been received. s have been received in Applicat rity documents have been receive u (PCT Rule 17.2(a)).	ion No ed in this National Stage			
Attachment(s)  1) Notice of References Cited (PTO-892)  2) Notice of Draftsperson's Patent Drawing Review (PTO-948)  3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08)  Paper No(s)/Mail Date	4) Interview Summary Paper No(s)/Mail D 5) Notice of Informal F 6) Other:				

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#### **DETAILED ACTION**

Claims 1-33 are presented for examination.

#### Information Disclosure Statement

The examiner has considered the applicant's Disclosure Statements of 3/27/2003.

## **Drawings**

- 1. The drawings are objected to because:
  - a. FIG.1 logic components 195 are referenced as 195a-d in the disclosure.
  - b. FIG.2 LSSD and STEP CLKS are not referred to in the disclosure.
  - FIG.9 LSSD\_CLKA, LSSD\_CLKB, LBST\_SCAN\_CLKA and LBST\_SDCAN\_CLKB are not referred to in the disclosure.

A proposed drawing correction or corrected drawings are required in reply to the Office action to avoid abandonment of the application. The objection to the drawings will not be held in abeyance.

## Specification

2. The disclosure is objected to because of the following informalities: page 7 line 8 describes engine 110 being configured by a 66 bit signal composed of a 32 bit vector and 33 bit seed. The sum of 32 and 33 is not 66. Appropriate correction is required.

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3. The disclosure is objected to because of the following informalities: page 9 line 24 recites, "(bits  $B_{26}$  to  $B_0$ )", but the examiner believes that it should read, "(bits  $B_{30}$  to  $B_0$ )". Appropriate correction is required.

- 4. The disclosure is objected to because of the following informalities: page 9 line 34 recites, "LBST\_STEP\_STEPE", but the examiner cannot find this reference in FIG.9. Appropriate correction is required.
- 5. The disclosure is objected to because of the following informalities: page 10 line 8 recites, "components 150", but the examiner cannot find this reference in the drawings. Appropriate correction is required.
- 6. The disclosure is objected to because of the following informalities: page 13 lines 28 and 30 recite, "ASIC 100", but the examiner cannot find this reference in the drawings, and believes it should read "ASIC 150". Appropriate correction is required.
- 7. The disclosure is objected to because of the following informalities: page 13 line 31 recites, "925 including", but the examiner cannot find this reference in the drawings. Appropriate correction is required.
- 8. The disclosure is objected to because of the following informalities: page 14 line 8 recites, "controller 925", but the examiner cannot find this reference in the drawings. Appropriate correction is required.

Claim Objections

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9. Claims 24, 25 and 31 are objected to because of the following informalities: in order to achieve a clearer understanding of the claim, the examiner suggests dropping the word "is" in each claim. Appropriate correction is required.

## Claim Rejections - 35 USC § 112

The following is a quotation of the second paragraph of 35 U.S.C. 112:

The specification shall conclude with one or more claims particularly pointing out and distinctly claiming the subject matter which the applicant regards as his invention.

- 10. Claims 23 and 30 recite the limitation "the first primitive polynomial" in line 1 and
- 2. There is insufficient antecedent basis for this limitation in the claim.
- 11. Claim 26 recites the limitation "the dual mode built-in self-test controller" in line 4. There is insufficient antecedent basis for this limitation in the claim.

### Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

The factual inquiries set forth in *Graham* v. *John Deere Co.*, 383 U.S. 1, 148 USPQ 459 (1966), that are applied for establishing a background for determining obviousness under 35 U.S.C. 103(a) are summarized as follows:

- 1. Determining the scope and contents of the prior art.
- 2. Ascertaining the differences between the prior art and the claims at issue.

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3. Resolving the level of ordinary skill in the pertinent art.

4. Considering objective evidence present in the application indicating obviousness or nonobviousness.

12. Claims 1, 3, 5, 8, 10, 22, 24 and 25 are rejected under 35 U.S.C. 103(a) as being unpatentable over McNamara et al., U.S. Patent No. 6629281, and in view of Heon-Cheol Kim, U.S. Patent No. 5938784.

As per Claim 1, 5, 8 and 22:

McNamara et al. teaches a BIST method and controller (see Abstract and column 1 lines33-44) comprising a LBIST engine (column 3 lines 27-31) and means for executing a LBIST (column 4 lines 27-28 and line 43), including an LBIST state machine (column 1 lines 44-48). McNamara et al. also teaches a pattern generator (column 1 lines 60-61) and storing compressed signature results (column 1 lines 60-67) but fails to teach the pattern generator as being based on a 1<sup>st</sup> primitive polynomial, and the signature register to be a MISR, based on a 2<sup>nd</sup> primitive polynomial. In an analogous art, Kim teaches prior art and the Kim invention as having an LFSR (pattern generator) and a MISR, both being based on primitive polynomials (see Abstract, column 1 lines 33-59 and column 2 lines 1-6 and column s lines 20-67 and column 4 lines 1-28). And Kim, in column 1 lines 60-67 and column 2 lines 1-9 states that the invention reduces the number of dedicated logic for the BIST controller. One with ordinary skill in the art at the time of the invention, motivated as suggested by Kim, would combine the two references, and so the claims are rejected.

As per Claims 3, 10, 24 and 25:

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Dependent on Claims 1 or 8 or 22, the claims limit the  $2^{nd}$  primitive polynomial to  $x^{32} + x^{28} + x + 1$ . The primitive polynomials available to the user in Kim, due to the broad scope, includes this polynomial by default, and in view of the previous motivation in Claims 1, 8 and 22, the claims are rejected.

- 13. Claims 2, 9 and 23 are rejected under 35 U.S.C. 103(a) as being unpatentable over McNamara et al., U.S. Patent No. 6629281, in view of Heon-Cheol Kim, U.S. Patent No. 5938784 as applied to Claims 1 or 22, and further in view of Paul H. Bardell Jr., U.S. Patent No. 4959832. Dependent on Claims 1 or 8 or 22, the claims limit the 1st primitive polynomial to  $x^{31} + x^3 + 1$ . In an analogous art, Bardell Jr. teaches this specific primitive polynomial in column 8 line 36. And Bardell Jr., in column 2 lines 29-67 recites the advantage of increased effectiveness in BIST by using the subject phase shift enhancement. One with ordinary skill in the art at the time of the invention, motivated to better BIST effectiveness as suggested, would combine the references, and so the claims are rejected.
- 14. Claim 4 is rejected under 35 U.S.C. 103(a) as being unpatentable over McNamara et al., U.S. Patent No. 6629281, in view of Heon-Cheol Kim, U.S. Patent No. 5938784 as applied to Claim 1 above, and further in view of Simpson et al., U.S. Patent No. 5260950, Wong et al., U.S. Patent No. 6636997, and Bogholtz et al., U.S. Patent No. 5357523. The LBIST state machine in Claim 1 is further limited to a reset state entered via an external signal. Simpson et al. enters a reset state (column 1 lines 24-36) via an external reset signal (Drawing, RESET 11), but does not begin initializing the device with an LBIST run signal. And Simpson et al., in column 1 lines 5-9 states the

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advantage of being able to provide a reset signal the circuit under test to a safe state. In McNamara et al. the device enters an initiate state subsequent to a start ABIST signal (column 2 lines 55-67), and suggests a similar LBIST in the same invention (column 3 lines 27-32). An analogous art, Wong et al. in column 6 lines 26-50 teaches the states of scan, step, and complete (done) as specified by the applicant's claim. Wong et al., in column 2 lines 62-67, describes an advantage of the invention as being capable of both pseudo-random and functional testing, but does not complete the test by comparing the pattern generator to a counter set-point. Lastly, an analogous art, Bogholtz et al., teaches ending the BIST under the condition of comparing the pattern generator to a pre-set count (FIG.10 32 and column 8 lines 27-40), and column 2 lines 7-10 specify an advantage as being a way to flexibly configure the test parameters. And in view of the motivations stated within this paragraph, one with ordinary skill in the art at the time of the invention would combine all of the references above, and thus the claim is rejected. 15. Claims 7, 11 and 28 are rejected under 35 U.S.C. 103(a) as being unpatentable over McNamara et al., U.S. Patent No. 6629281, and in view of Heon-Cheol Kim, U.S. Patent No. 5938784 as applied to Claims 1 or 8 or 22 above, and in view of Rajski et al., U.S. Patent No. 5991909. Dependent on Claims 1 or 8 or 22 above, the claims limit the seeding of the pattern generator to being externally configurable. In an analogous art, Rajski et al. sets the LFSR (column 7 lines 15-23) to an external seed (FIG.3 108) via an input port. And Rajski et al., in column 3 lines 31-34 recites the advantage of testing with variable reseeding that is compatible with JTAG protocols. One with ordinary skill in

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the art at the time of the invention, motivated by Rajski et al. as indicated, would combine the references, and so the claims are rejected.

16. Claims 6, 12, 14, 16, 17, 18 and 27 are rejected under 35 U.S.C. 103(a) as being unpatentable over McNamara et al., U.S. Patent No. 6629281, in view of Heon-Cheol Kim, U.S. Patent No. 5938784, and further in view of Motika et al., U.S. Patent No. 5982189.

As per Claims 6, 17 and 27:

Dependent on Claims 1 or 12 or 22, the claims further limit the controller wherein the signature register includes a bit indicating the LBIST is done. Motika et al., in column 3 lines 39-67 and column 4 lines 1-5 teaches a LBIST where the signature includes a pass/fail indicator. A pass/fail indicator is the same as a test done indicator — the testing must be done if there is a pass/fail indication. And column 1 lines 65-67 specifies of Motika et al. recites an advantage to be a better stress test for circuits. One with ordinary skill in the art at the time of the invention, motivated by Motika et al., would combine the references, and so the claims are rejected.

As per Claim 12, 16 and 18:

McNamara et al. teaches a BIST controller (see Abstract and column 1 lines33-44) comprising a LBIST or MBIST engine (column 3 lines 27-31) and means for executing a LBIST or MBIST (column 4 lines 27-28 and line 43), including an LBIST or MBIST state machine (column 1 lines 44-48). McNamara et al. also teaches a pattern generator (column 1 lines 60-61) and storing compressed signature results (column 1 lines 60-67) but fails to teach the pattern generator as being based on a 1<sup>st</sup> primitive

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polynomial, and the signature register to be a MISR, based on a 2<sup>nd</sup> primitive polynomial. In an analogous art, Kim teaches prior art and the Kim invention as having an LFSR (pattern generator) and a MISR, both being based on primitive polynomials (see Abstract, column 1 lines 33-59 and column 2 lines 1-6 and column s lines 20-67 and column 4 lines 1-28). And Kim, in column 1 lines 60-67 and column 2 lines 1-9 states that the invention reduces the number of dedicated logic for the BIST controller. However, the references fail to teach a plurality of memory components, a logic core, and a testing interface. In an analogous art, Motika et al. teaches these features in FIG.2 as memories (FIG.2 36), a logic core (FIG.2 38), and tester interface (FIG.2 60). One with ordinary skill in the art at the time of the invention, motivated as suggested by Kim above and Motika et al. elsewhere in this office action would combine the references, and so the claims are rejected.

## As per Claim 14:

Dependent on Claim 12, the claim limits the  $2^{nd}$  primitive polynomial to  $x^{32} + x^{28} + x + 1$ . The primitive polynomials available to the user in Kim, due to the broad scope, includes this polynomial by default, and in view of the previous motivation in Claim 12, the claim is rejected.

17. Claim 13 is rejected under 35 U.S.C. 103(a) as being unpatentable over McNamara et al., U.S. Patent No. 6629281, in view of Heon-Cheol Kim, U.S. Patent No. 5938784, and further in view of Motika et al., U.S. Patent No. 5982189 as applied to Claim 12, and further in view of Paul H. Bardell Jr., U.S. Patent No. 4959832.

Dependent on Claim 12, the claim limits the 1st primitive polynomial to  $x^{31} + x^3 + 1$ . In

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an analogous art, Bardell Jr. teaches this specific primitive polynomial in column 8 line 36. And Bardell Jr., in column 2 lines 29-67 recites the advantage of increased effectiveness in BIST by using the subject phase shift enhancement. One with ordinary skill in the art at the time of the invention, motivated to better BIST effectiveness as suggested, would combine the references, and so the claim is rejected.

18. Claim 15 is rejected under 35 U.S.C. 103(a) as being unpatentable over McNamara et al., U.S. Patent No. 6629281, in view of Heon-Cheol Kim, U.S. Patent No. 5938784, and further in view of Motika et al., U.S. Patent No. 5982189 as applied to Claim 12 above, and further in view of of Simpson et al., U.S. Patent No. 5260950, Wong et al., U.S. Patent No. 6636997, and Bogholtz et al., U.S. Patent No. 5357523. The LBIST state machine in Claim 12 is further limited to a reset state entered via an external signal. Simpson et al. enters a reset state (column 1 lines 24-36) via an external reset signal (Drawing, RESET 11), but does not begin initializing the device with an LBIST run signal. And Simpson et al., in column 1 lines 5-9 states the advantage of being able to provide a reset signal the circuit under test to a safe state. In McNamara et al. the device enters an initiate state subsequent to a start ABIST signal (column 2 lines 55-67), and suggests a similar LBIST in the same invention (column 3 lines 27-32). An analogous art, Wong et al. in column 6 lines 26-50 teaches the states of scan, step, and complete (done) as specified by the applicant's claim. Wong et al., in column 2 lines 62-67, describes an advantage of the invention as being capable of both pseudo-random and functional testing, but does not complete the test by comparing the pattern generator to a counter set-point. Lastly, an analogous art, Bogholtz et al.,

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teaches ending the BIST under the condition of comparing the pattern generator to a pre-set count (FIG.10 32 and column 8 lines 27-40), and column 2 lines 7-10 specify an advantage as being a way to flexibly configure the test parameters. And in view of the motivations stated within this paragraph, one with ordinary skill in the art at the time of the invention would combine all of the references above, and thus the claim is rejected.

- 19. Claim 19 is rejected under 35 U.S.C. 103(a) as being unpatentable over McNamara et al., U.S. Patent No. 6629281, in view of Heon-Cheol Kim, U.S. Patent No. 5938784, and in view of Motika et al., U.S. Patent No. 5982189 as applied to Claim 12 above, and further in view of Kim et al., U.S. Patent No. 6148426. Dependent on Claim 12, this claim limits a memory device to being a static random access memory. In an analogous art, Kim et al. teaches an MBIST (see Abstract) that is used for testing an SRAM (see Title). Citing a savings in BIST size and cost (column 2 lines 55-61), Kim et al. would motivate one with ordinary skill in the art at the time of the invention to combine the art for the purpose of testing SRAM memories.
- 20. Claim 20 is rejected under 35 U.S.C. 103(a) as being unpatentable over McNamara et al., U.S. Patent No. 6629281, in view of Heon-Cheol Kim, U.S. Patent No. 5938784, and in view of Motika et al., U.S. Patent No. 5982189 as applied to Claim 12 above, and further in view of Au et al., U.S. Patent No. 6681359. Dependent on Claim 12, this claim limits a test interface to a JTAG TAP Controller. In Au et al., FIG.3 112 is a JTAG TAP Controller, and Au et al., in column 2 lines 18-27 in reciting the attributes of the invention, boasts of a better means to retrieve information within an MBIST while not requiring a large number of device pins. One with ordinary skill in the art at the time of

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the invention, motivated by Au et al., would combine the two references, thus the claims are rejected.

21. Claim 21 is rejected under 35 U.S.C. 103(a) as being unpatentable over McNamara et al., U.S. Patent No. 6629281, in view of Heon-Cheol Kim, U.S. Patent No. 5938784, and in view of Motika et al., U.S. Patent No. 5982189 as applied to Claim 12 above, and further in view of Rajski et al., U.S. Patent No. 5991909. Dependent on Claim 12 above, the claim limits the seeding of the pattern generator to being externally configurable. In an analogous art, Raiski et al. sets the LFSR (column 7 lines 15-23) to an external seed (FIG.3 108) via an input port. And Rajski et al., in column 3 lines 31-34 recites the advantage of testing with variable reseeding that is compatible with JTAG protocols. One with ordinary skill in the art at the time of the invention, motivated by Rajski et al. as indicated, would combine the references, and so the claims are rejected. 22. Claim 26 is rejected under 35 U.S.C. 103(a) as being unpatentable over McNamara et al., U.S. Patent No. 6629281, in view of Heon-Cheol Kim, U.S. Patent No. 5938784, as applied to Claim 22 above, and further in view of Wong et al., U.S. Patent No. 6636997, and Bogholtz et al., U.S. Patent No. 5357523. The LBIST method of Claim 22 is further defined whereas it initializes the device with an LBIST run signal. In McNamara et al. the device enters an initiate state subsequent to a start ABIST signal (column 2 lines 55-67), and suggests a similar LBIST in the same invention (column 3 lines 27-32). An analogous art, Wong et al. in column 6 lines 26-50 teaches the states of scan, step, and complete (done) as specified by the applicant's claim. Wong et al., in column 2 lines 62-67, describes an advantage of the invention as being capable of both

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pseudo-random and functional testing, but does not complete the test by comparing the pattern generator to a counter set-point. Lastly, an analogous art, Bogholtz et al., teaches ending the BIST under the condition of comparing the pattern generator to a pre-set count (FIG.10 32 and column 8 lines 27-40), and column 2 lines 7-10 specify an advantage as being a way to flexibly configure the test parameters. And in view of the motivations stated within this paragraph, one with ordinary skill in the art at the time of the invention would combine all of the references above, and thus the claim is rejected.

23. Claims 29, 31, 32 and 33 are rejected under 35 U.S.C. 103(a) as being unpatentable over Au et al., U.S. Patent No. 6681359, in view of Rajski et al., U.S. Patent No. 5991909, in view of Heon-Cheol Kim, U.S. Patent No. 5938784.

As for Claim 29:

Au et al. teaches a method for testing an integrated circuit device (see Abstract), the method comprising: interfacing the integrated circuit device with a tester (column 8 lines 29-31); performing a built-in self-test (column 8 lines 56-58), and reading the indication (column 10 lines 21-26). Au et al. however fails to teach, seeding a pattern generator with a 1<sup>st</sup> polynomial, performing a LBIST and storing results in a MISR using a 2<sup>nd</sup> primitive polynomial. In an analogous art, Rajski et al. does teach seeding a pattern generator (FIG.3 106 and column 3 lines 59-62 and column 7 line 18) with any polynomial (column 8 line 64), performing a LBIST (column 1 lines 5-10), and storing results in a MISR (FIG.1 28), but does not teach using a primitive polynomial in the MISR. But Kim does teach using a primitive polynomial (see Kim Absract). And in view of the motivation previously set forth for Rajski et al. and Kim, one with ordinary skill in

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the art at the time of the invention would combine the references, and so the claim is rejected.

## As per Claim 31:

Dependent on Claim 29, the claim limits the  $2^{nd}$  primitive polynomial to  $x^{32} + x^{28} + x + 1$ . The primitive polynomials available to the user in Kim, due to the broad scope, includes this polynomial by default, and in view of the previous motivation in Claims 29, the claim is rejected.

#### As per Claim 32:

The method of Claim 29 is limited to externally configuring the seed. Rajski et al., in FIG3 108 describes the same feature, and in view of the previous motivation, the claim is rejected.

## As per Claim 33:

The method of Claim 29 is further limited to performing a MBIST. Au et al., describes this feature in the Abstract, and in view of the motivation previously mentioned, the claim is rejected.

24. Claim 30 is rejected under 35 U.S.C. 103(a) as being unpatentable over Au et al., U.S. Patent No. 6681359, in view of Rajski et al., U.S. Patent No. 5991909, and in view of Heon-Cheol Kim, U.S. Patent No. 5938784 as applied to Claim 29, and further in view of Paul H. Bardell Jr., U.S. Patent No. 4959832. Dependent on Claim 29, the claim limits the 1st primitive polynomial to  $x^{31} + x^3 + 1$ . In an analogous art, Bardell Jr. teaches this specific primitive polynomial in column 8 line 36. And Bardell Jr., in column 2 lines 29-67 recites the advantage of increased effectiveness in BIST by using the subject

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phase shift enhancement. One with ordinary skill in the art at the time of the invention, motivated to better BIST effectiveness as suggested, would combine the references, and so the claim is rejected.

#### Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to John P Trimmings whose telephone number is 703-305-0714. The examiner can normally be reached on weekdays, 7:30 AM to 4:00 PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Albert DeCady can be reached on 703-305-9595. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

John P Trimmings

Examiner

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jpt

Albert DeCadv **Primary Examiner**  Page 15